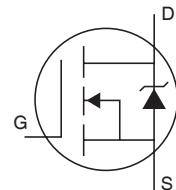


Features

- $V_{DS(V)} = 40V$
- $I_D = 75A$ ($V_{GS} = 10V$)
- $R_{DS(ON)} < 2.0m\Omega$ ($V_{GS} = 10V$)
- $R_{DS(ON)} < 2.3m\Omega$ ($V_{GS} = 4.5V$)



Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Silicon Limited)	270	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (See Fig. 9)	190	
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Package Limited)	75	
I_{DM}	Pulsed Drain Current ①	1080	
$P_D @ T_C = 25^\circ C$	Maximum Power Dissipation	300	W
	Linear Derating Factor	2.0	W/ $^\circ C$
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	540	mJ
E_{AS} (tested)	Single Pulse Avalanche Energy Tested Value ⑦	1160	
I_{AR}	Avalanche Current ①	See Fig.12a,12b,15,16	A
E_{AR}	Repetitive Avalanche Energy ⑥		mJ
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to +175	$^\circ C$
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Typ.	Max.	Units
R_{0JC}	Junction-to-Case		0.50 ⑩	$^\circ C/W$
R_{0CS}	Case-to-Sink, Flat, Greased Surface	0.50		
R_{0JA}	Junction-to-Ambient		62	
R_{0JA}	Junction-to-Ambient (PCB Mount, steady state) ⑧		40	

Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	40			V	$V_{GS} = 0V, I_D = 250\mu\text{A}$
$\Delta V_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.031		V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{\text{DS(on)}}$	Static Drain-to-Source On-Resistance		1.5	2.0	$\text{m}\Omega$	$V_{GS} = 10V, I_D = 75\text{A}$ ④
$R_{\text{DS(on)}}$	Static Drain-to-Source On-Resistance		1.8	2.3	$\text{m}\Omega$	$V_{GS} = 10V, I_D = 75\text{A}$ ④
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
g_{fs}	Forward Transconductance	130			S	$V_{DS} = 10V, I_D = 75\text{A}$
I_{DSS}	Drain-to-Source Leakage Current			20	μA	$V_{DS} = 40V, V_{GS} = 0V$
				250	μA	$V_{DS} = 40V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage			200	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-200	nA	$V_{GS} = -20V$
Q_g	Total Gate Charge	160	240		nC	$I_D = 75\text{A}$
Q_{gs}	Gate-to-Source Charge	41	62		nC	$V_{DS} = 32V$
Q_{gd}	Gate-to-Drain ("Miller") Charge	66	99		nC	$V_{GS} = 10V$ ④
$t_{d(on)}$	Turn-On Delay Time	13			ns	$V_{DD} = 20V$
t_r	Rise Time	120			ns	$I_D = 75\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	130			ns	$R_G = 2.5\Omega$
t_f	Fall Time	130			ns	$V_{GS} = 10V$ ④
L_D	Internal Drain Inductance	4.5			nH	Between lead, 6mm (0.25in.) from package and center of die contact
L_S	Internal Source Inductance	7.5			nH	
C_{iss}	Input Capacitance	6450			pF	$V_{GS} = 0V$
C_{oss}	Output Capacitance	1690			pF	$V_{DS} = 25V$
C_{rss}	Reverse Transfer Capacitance	840			pF	$f = 1.0\text{MHz}$, See Fig. 5
C_{oss}	Output Capacitance	5350			pF	$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0\text{MHz}$
C_{oss}	Output Capacitance	1520			pF	$V_{GS} = 0V, V_{DS} = 32V, f = 1.0\text{MHz}$
$C_{oss \text{ eff.}}$	Effective Output Capacitance	2210			pF	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 32V$
I_S	Continuous Source Current (Body Diode)			270	A	MOSFET symbol
I_{SM}	Pulsed Source Current (Body Diode) ①			1080	A	showing the integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^\circ\text{C}, I_S = 75\text{A}, V_{GS} = 0V$ ④
t_{rr}	Reverse Recovery Time	56	84	ns		$T_J = 25^\circ\text{C}, I_F = 75\text{A}, V_{DD} = 20V$
Q_{rr}	Reverse Recovery Charge	67	100	nC		$dI/dt = 100\text{A}/\mu\text{s}$ ④
t_{on}	Forward Turn-On Time					Intrinsic turn-on time is negligible (turn-on is dominated by $LS+LD$)

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Limited by $T_{J\text{max}}$, starting $T_J = 25^\circ\text{C}$, $L=0.24\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 75\text{A}$, $V_{GS} = 10V$. Part not recommended for use above this value.
- ③ $I_{SD} \leq 75\text{A}$, $di/dt \leq 220\text{A}/\mu\text{s}$, $V_{DD} \leq V_{(\text{BR})\text{DSS}}$, $T_J \leq 175^\circ\text{C}$.
- ④ Pulse width $\leq 1.0\text{ms}$; duty cycle $\leq 2\%$.
- ⑤ $C_{oss \text{ eff.}}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- ⑥ Limited by $T_{J\text{max}}$, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- ⑦ This value determined from sample failure population. 100% tested to this value in production.
- ⑧ This is applied to D²Pak, when mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- ⑨ Max $R_{\text{DS(on)}}$ for D²Pak and TO-262 (SMD) devices.
- ⑩ TO-220 device will have an R_{th} value of $0.45^\circ\text{C}/\text{W}$.

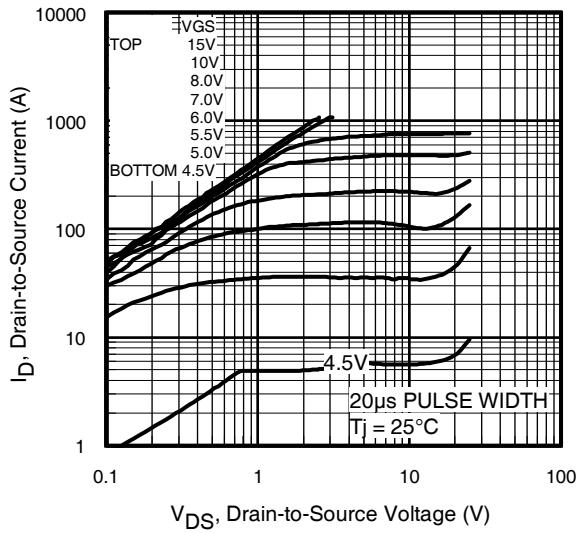


Fig 1. Typical Output Characteristics

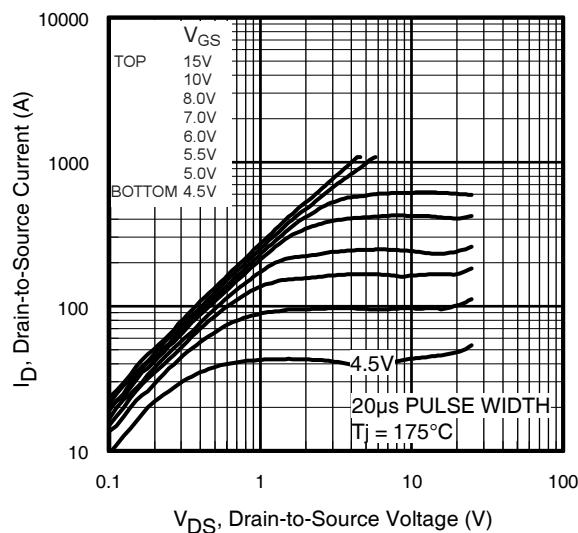


Fig 2. Typical Output Characteristics

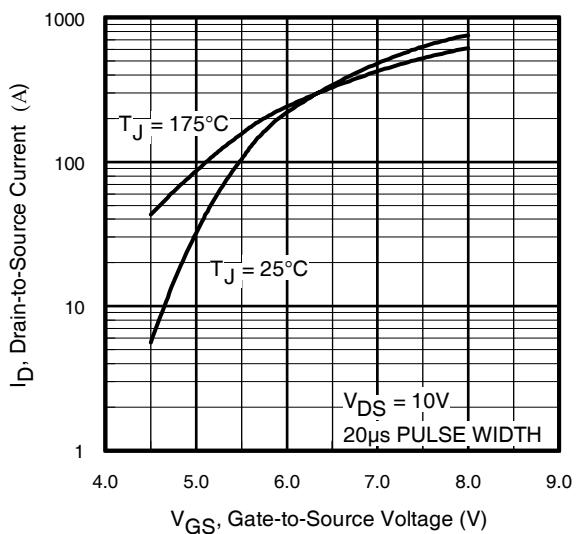


Fig 3. Typical Transfer Characteristics

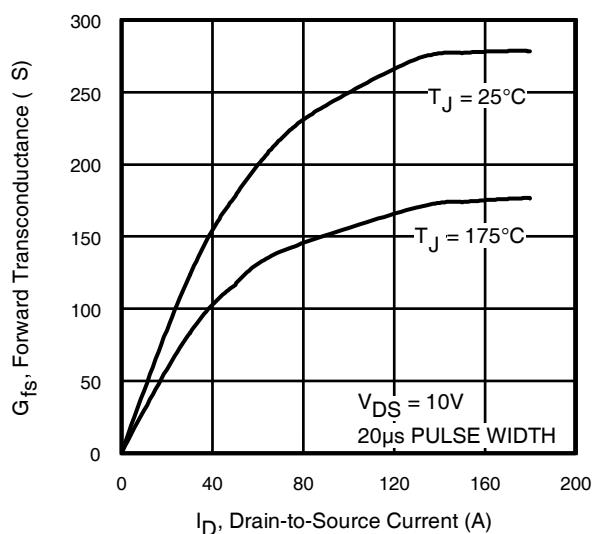


Fig 4. Typical Forward Transconductance vs. Drain Current

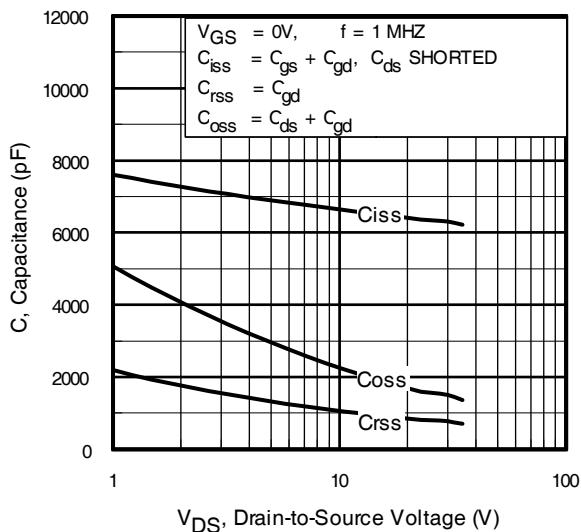


Fig 5. Typical Capacitance vs.
Drain-to-Source Voltage

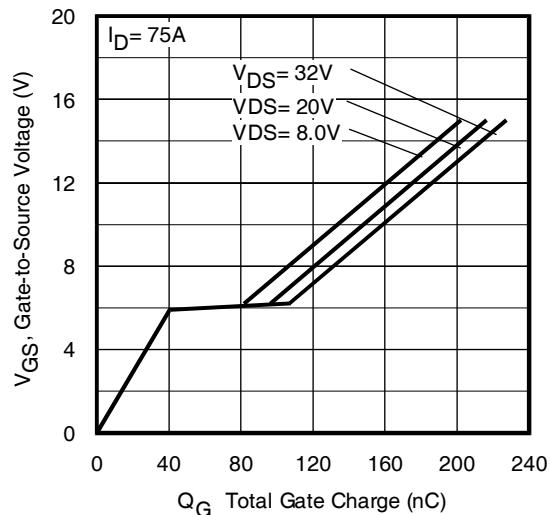


Fig 6. Typical Gate Charge vs.
Gate-to-Source Voltage

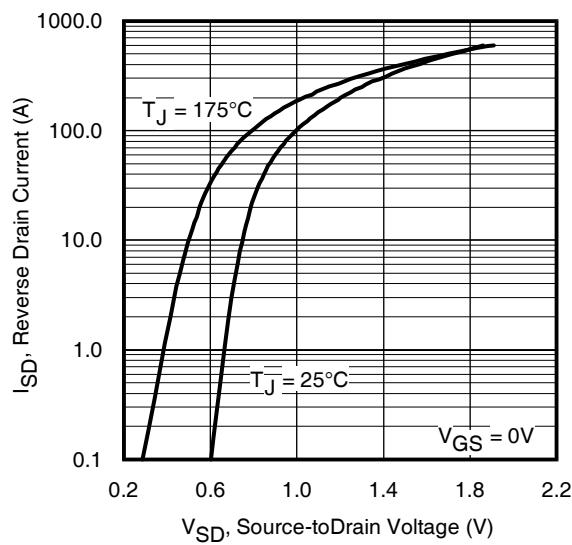


Fig 7. Typical Source-Drain Diode
Forward Voltage

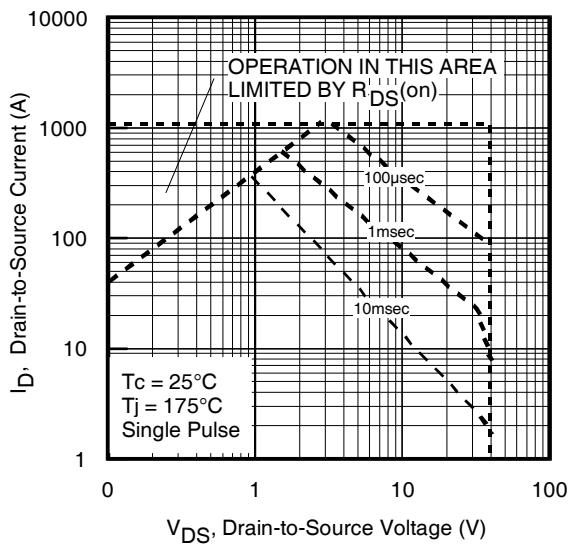


Fig 8. Maximum Safe Operating Area

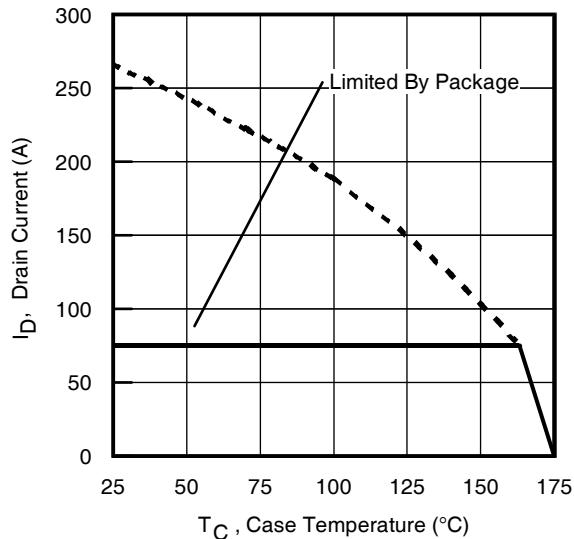


Fig 9. Maximum Drain Current vs. Case Temperature

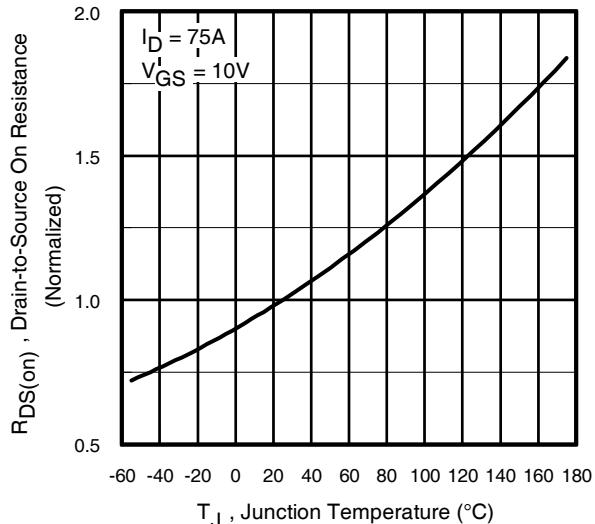


Fig 10. Normalized On-Resistance vs. Temperature

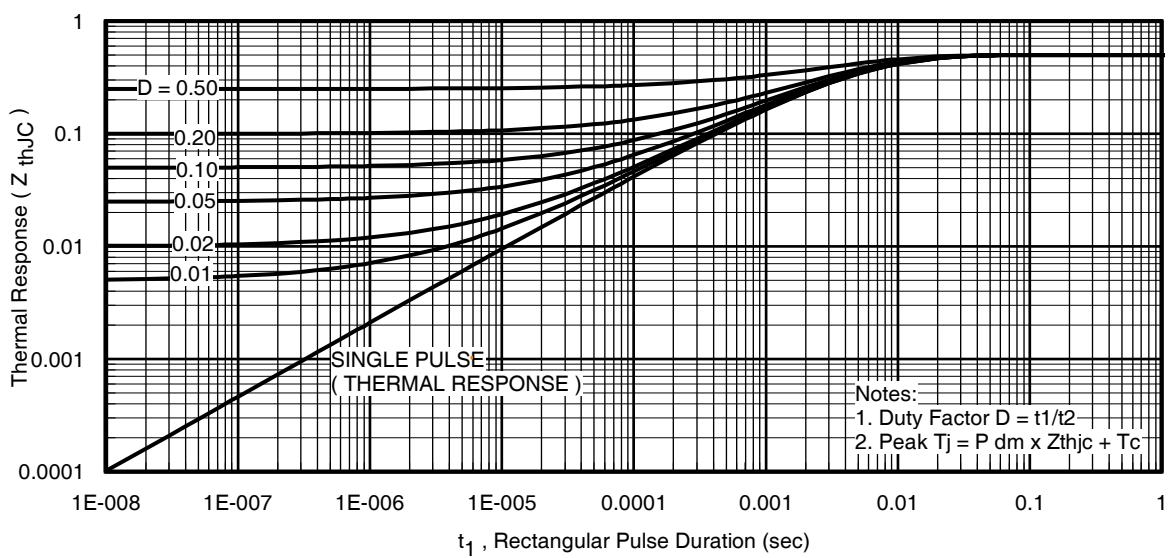


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

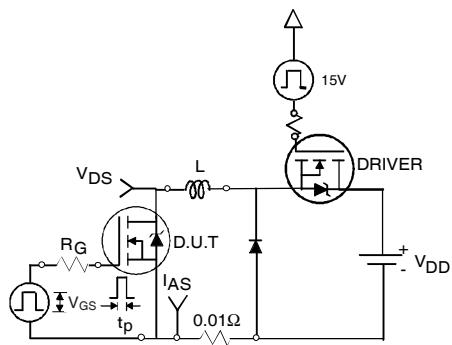


Fig 12a. Unclamped Inductive Test Circuit

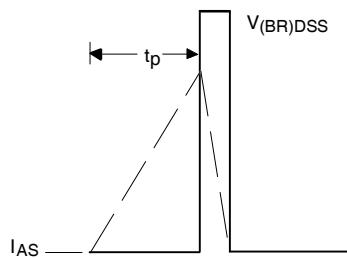


Fig 12b. Unclamped Inductive Waveforms

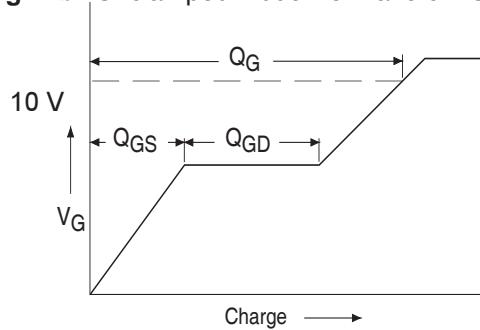


Fig 13a. Basic Gate Charge Waveform

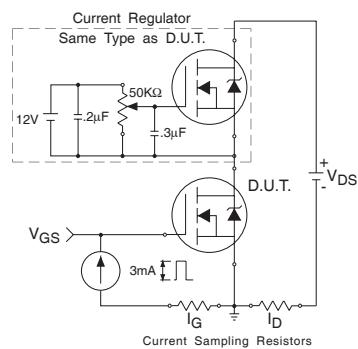


Fig 13b. Gate Charge Test Circuit

6

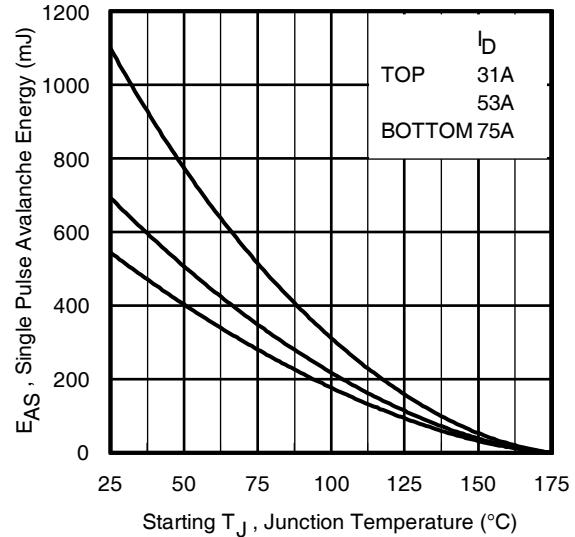


Fig 12c. Maximum Avalanche Energy vs. Drain Current

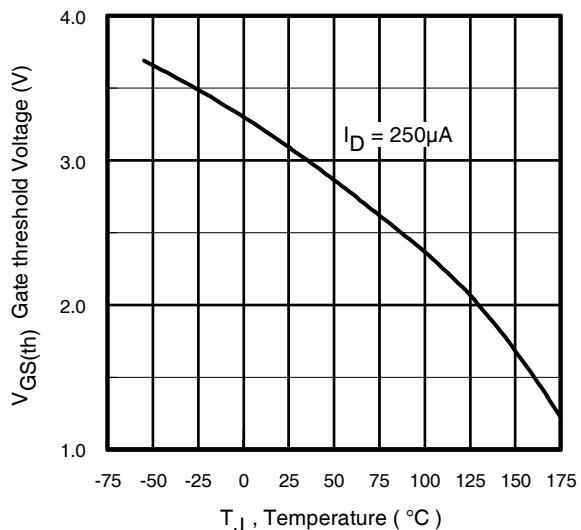


Fig 14. Threshold Voltage vs. Temperature

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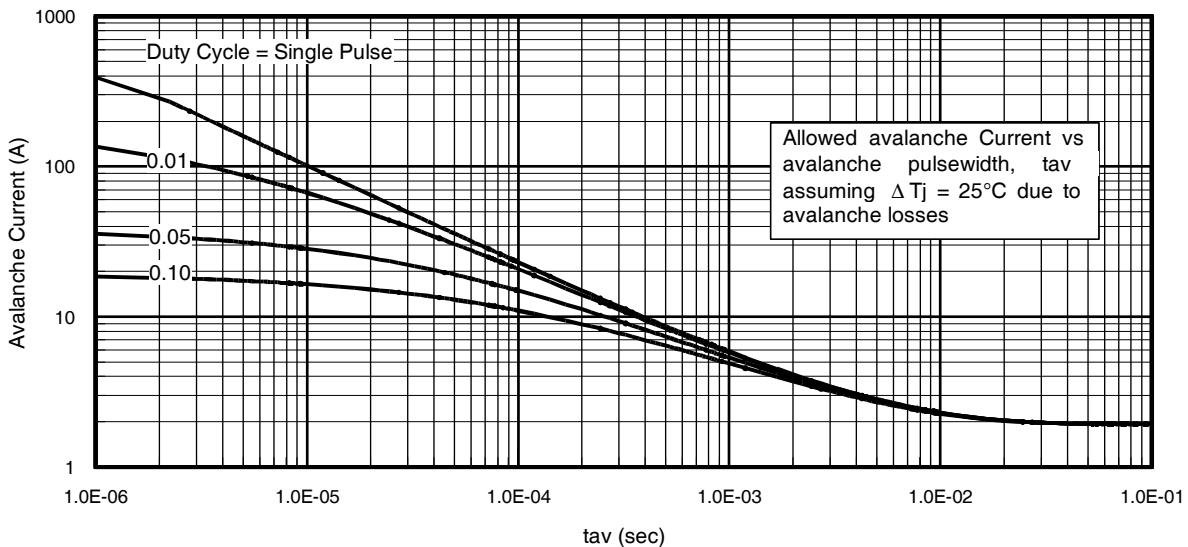


Fig 15. Typical Avalanche Current Vs.Pulsewidth

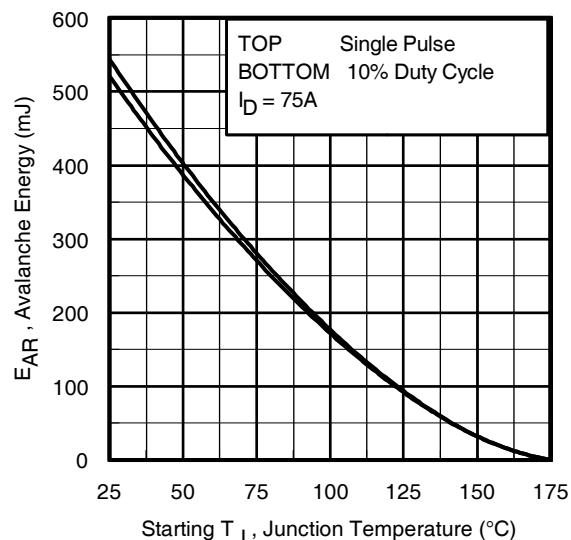


Fig 16. Maximum Avalanche Energy vs. Temperature

1. Avalanche failures assumption:
Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
4. $P_{D(ave)} = \text{Average power dissipation per single avalanche pulse.}$
5. $BV = \text{Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).}$
6. $I_{av} = \text{Allowable avalanche current.}$
7. $\Delta T = \text{Allowable rise in junction temperature, not to exceed } T_{jmax} \text{ (assumed as } 25^\circ\text{C in Figure 15, 16).}$
- $t_{av} = \text{Average time in avalanche.}$
- $D = \text{Duty cycle in avalanche} = t_{av} \cdot f$
- $Z_{thJC}(D, t_{av}) = \text{Transient thermal resistance, see figure 11}$

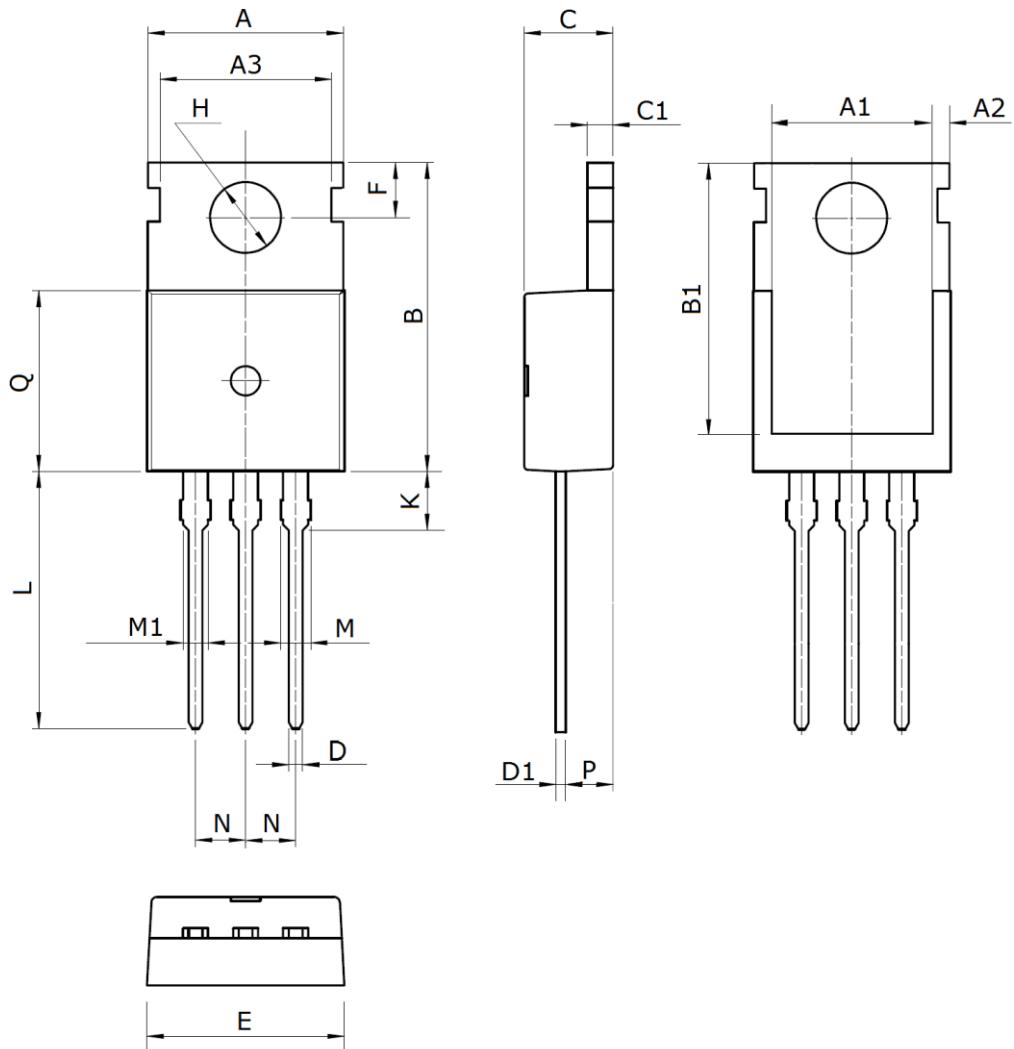
$$P_{D(ave)} = 1/2 (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$$

$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

$$E_{AS(AR)} = P_{D(ave)} \cdot t_{av}$$

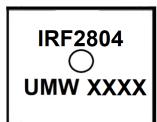
Package Dimensions

TO 220



Symbol	Dimensions (mm)	Symbol	Dimensions (mm)	Symbol	Dimensions (mm)
A	10.0±0.3	C1	1.3±0.2	L	13.2±0.4
A1	8.0±0.2	D	0.8±0.2	M	1.38±0.1
A2	0.94±0.1	D1	0.5±0.1	M1	1.28±0.1
A3	8.7±0.1	E	10.0±0.3	N	2.54(typ)
B	15.6±0.4	F	2.8±0.1	P	2.4±0.3
B1	13.2±0.2	H	3.6±0.1	Q	9.15±0.25
C	4.5±0.2	K	3.1±0.2		

Marking



Ordering information

Order code	Package	Baseqty	Deliverymode
UMW IRF2804PBF	TO-220	1000	Tube and box

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[DMN2990UFB-7B](#) [SSM3K35CT,L3F](#) [IPLK60R1K0PFD7ATMA1](#) [2N7002W-G](#) [MCAC30N06Y-TP](#) [IPWS65R035CFD7AXKSA1](#)
[MCQ7328-TP](#) [SSM3J143TU,LXHF](#) [DMN12M3UCA6-7](#) [PJMF280N65E1_T0_00201](#) [PJMF380N65E1_T0_00201](#)
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